

Device Modeling Report

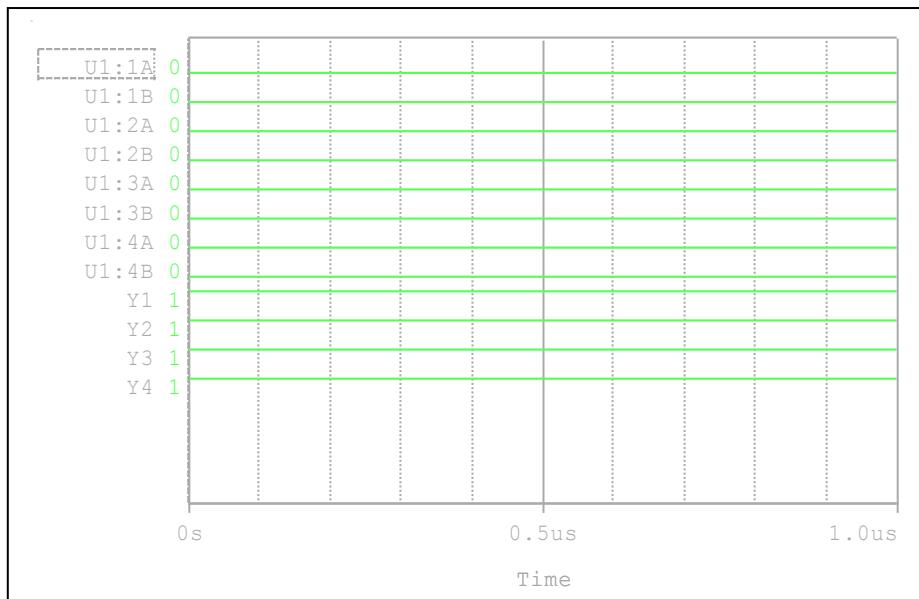
COMPONENTS : CMOS DIGITAL INTEGRATED CIRCUIT
PART NUMBER : TC74ACT00F
MANUFACTURER : TOSHIBA



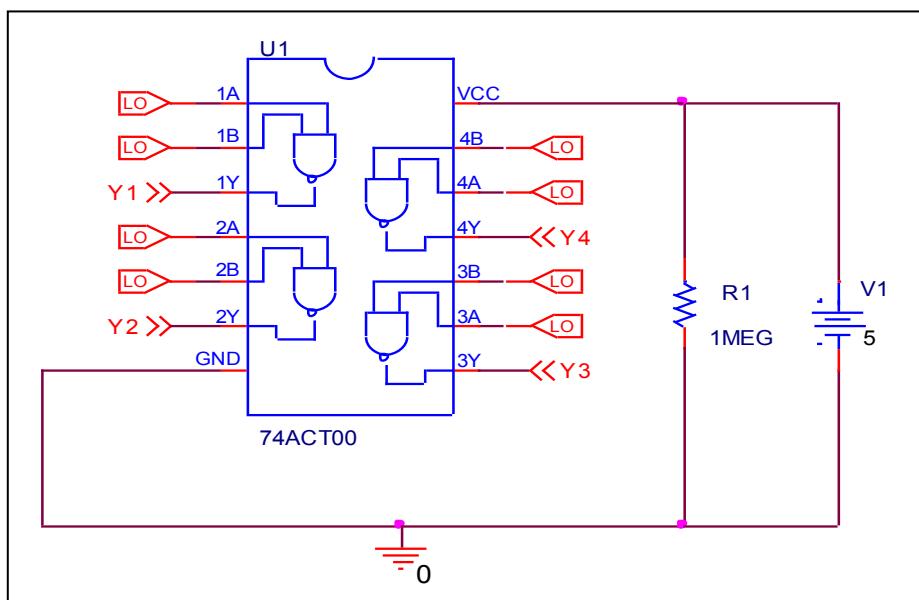
Bee Technologies Inc.

Truth Table

Circuit simulation result



Evaluation circuit

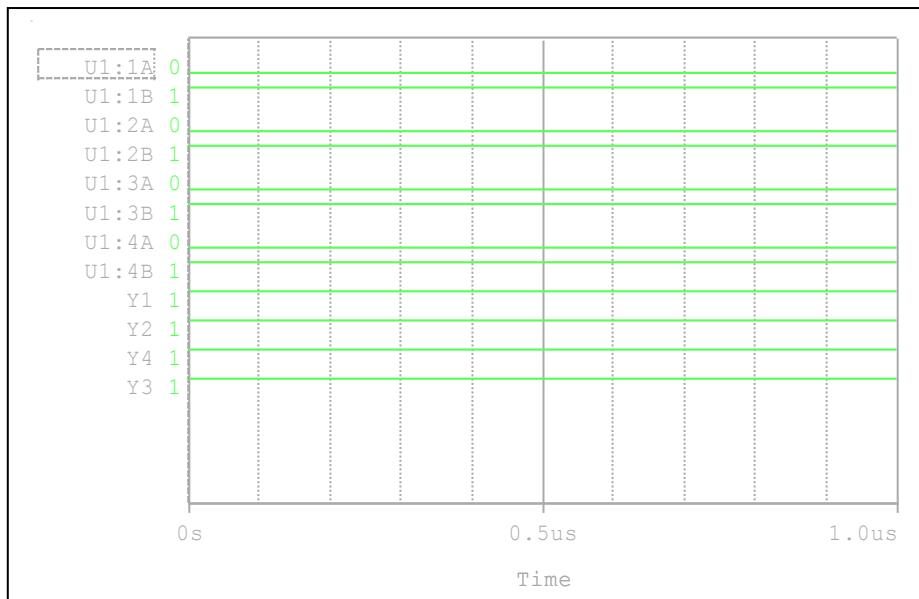


Comparison table

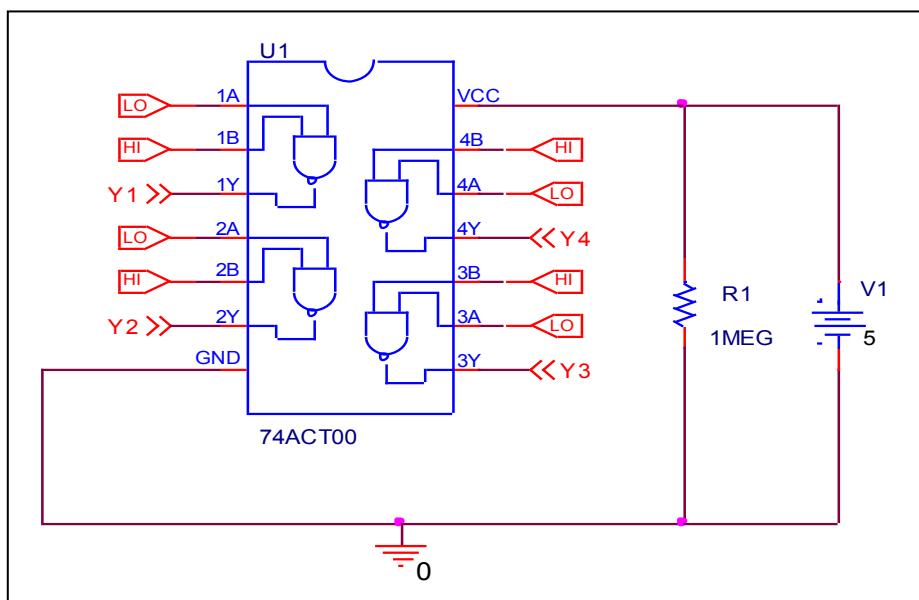
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

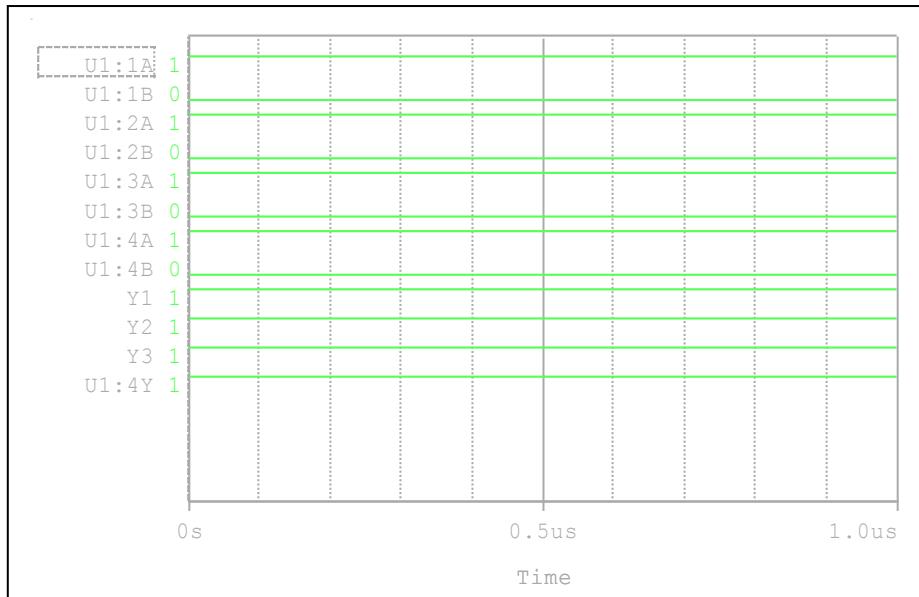


Comparison table

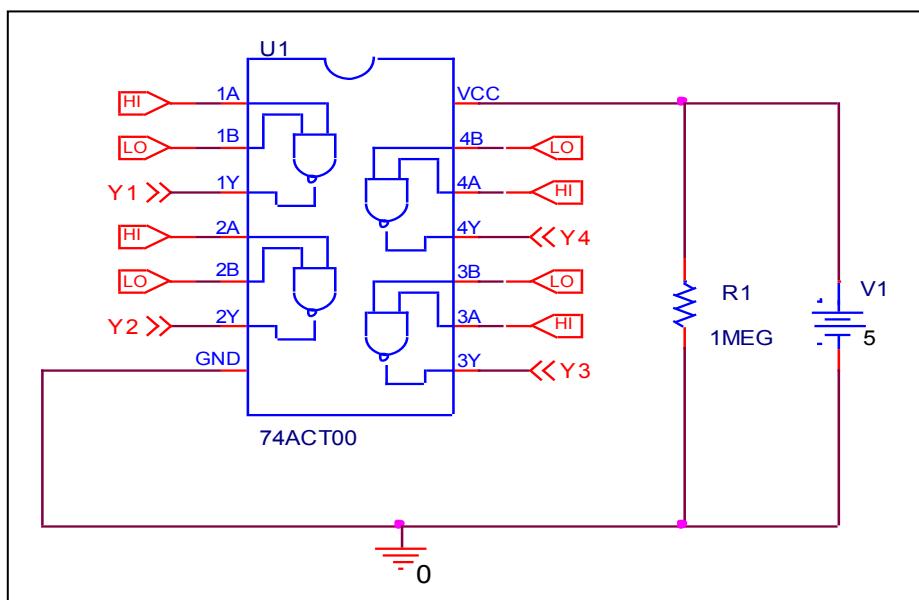
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
L	H	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

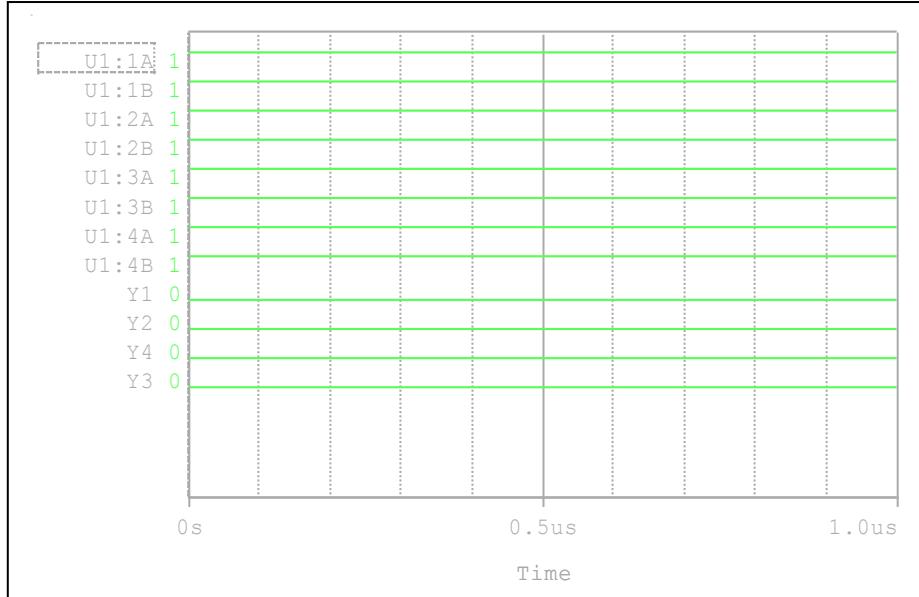


Comparison table

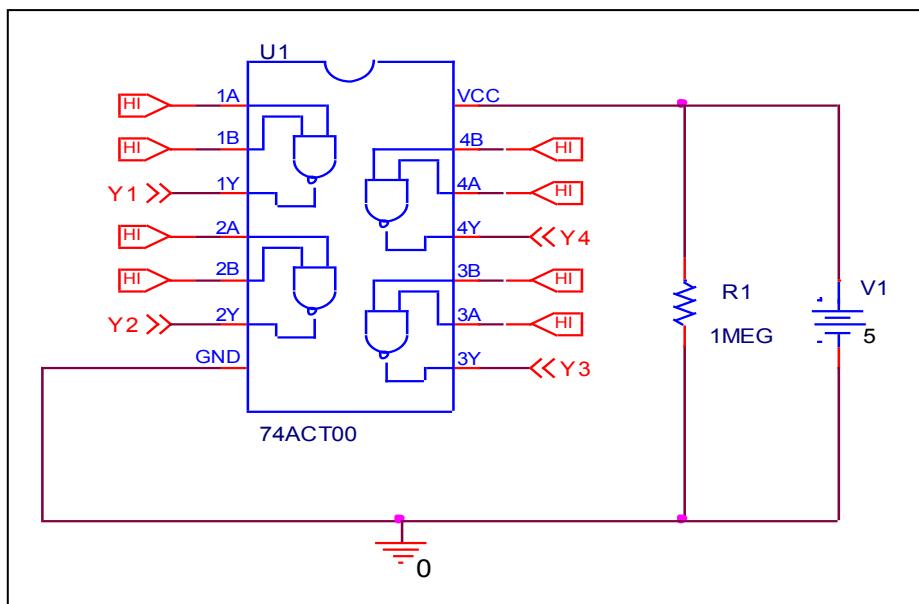
Input		Output		%Error
A _n	B _n	Y _n (Measurement)	Y _n (Simulation)	
H	L	H	H	0

Truth Table

Circuit simulation result



Evaluation circuit

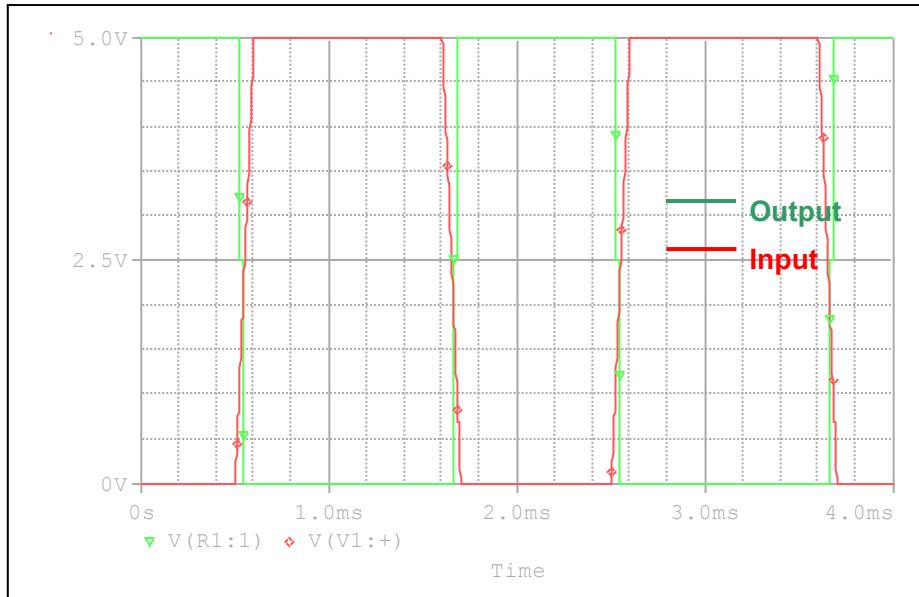


Comparison table

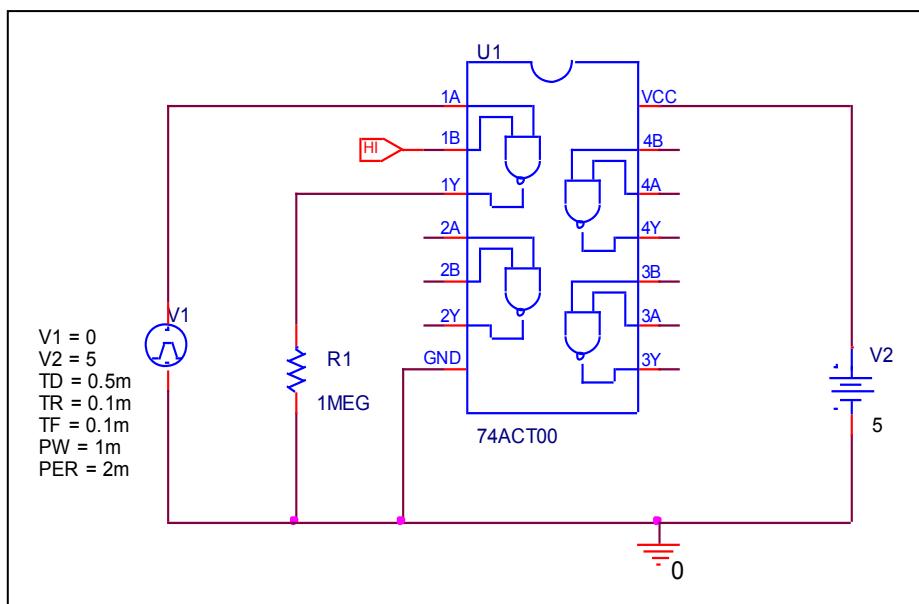
Input		Output		%Error
An	Bn	Yn (Measurement)	Yn (Simulation)	
H	H	L	L	0

High Level and Low Level Input Voltage

Circuit simulation result



Evaluation circuit

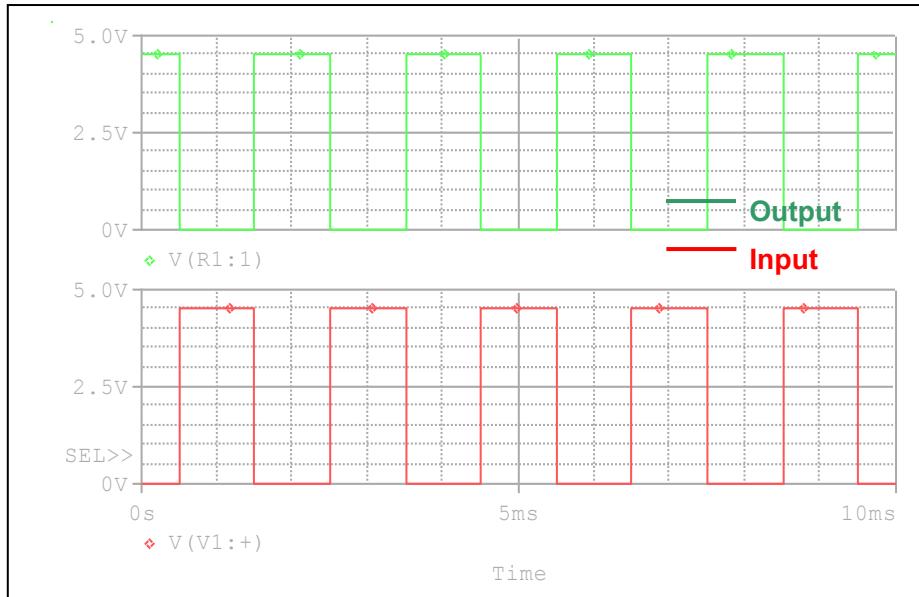


Comparison table

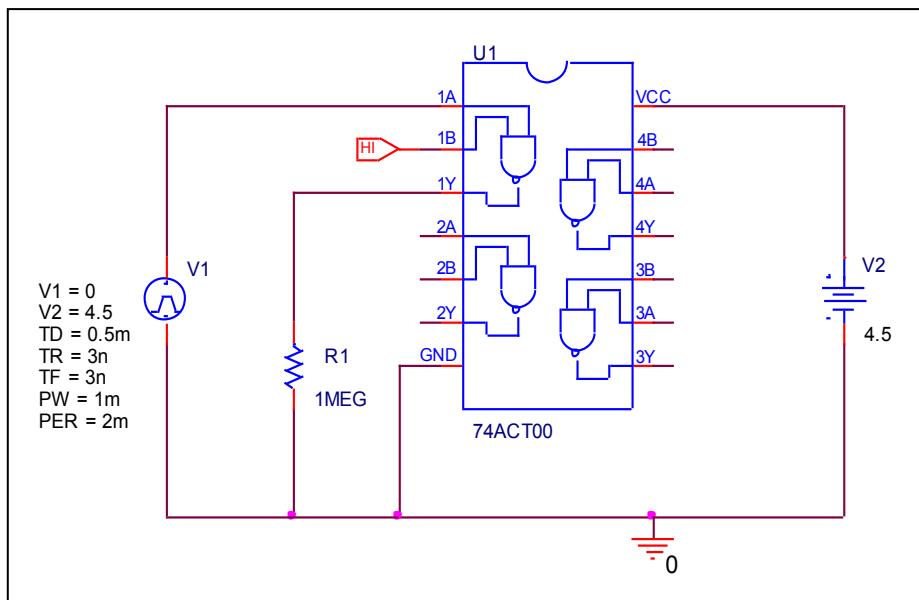
V _{cc} = 5V	Measurement	Simulation	%Error
V _{IH} (V)	2	2	0
V _{IL} (V)	0.8	0.799220	-0.098

High Level and Low Level Output Voltage

Circuit simulation result



Evaluation circuit

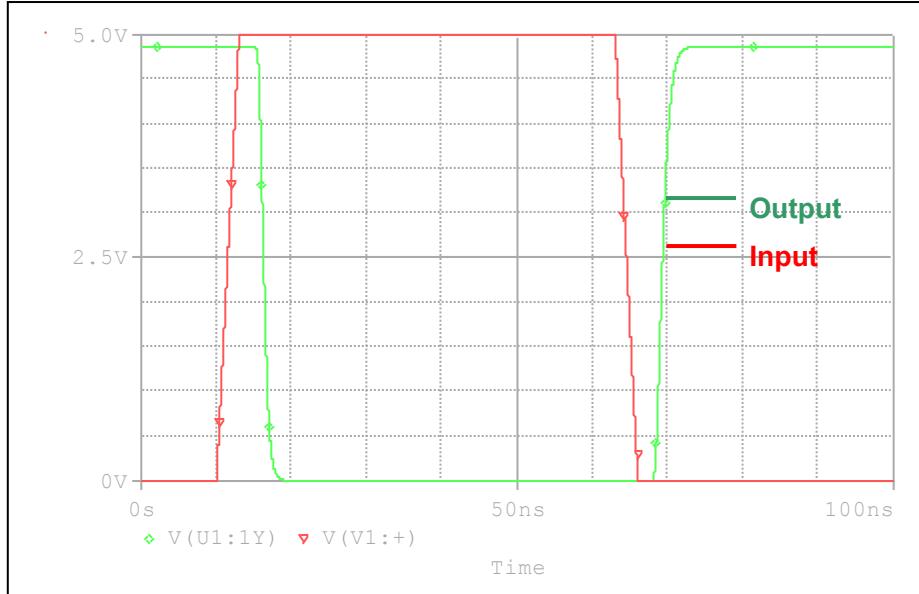


Comparison table

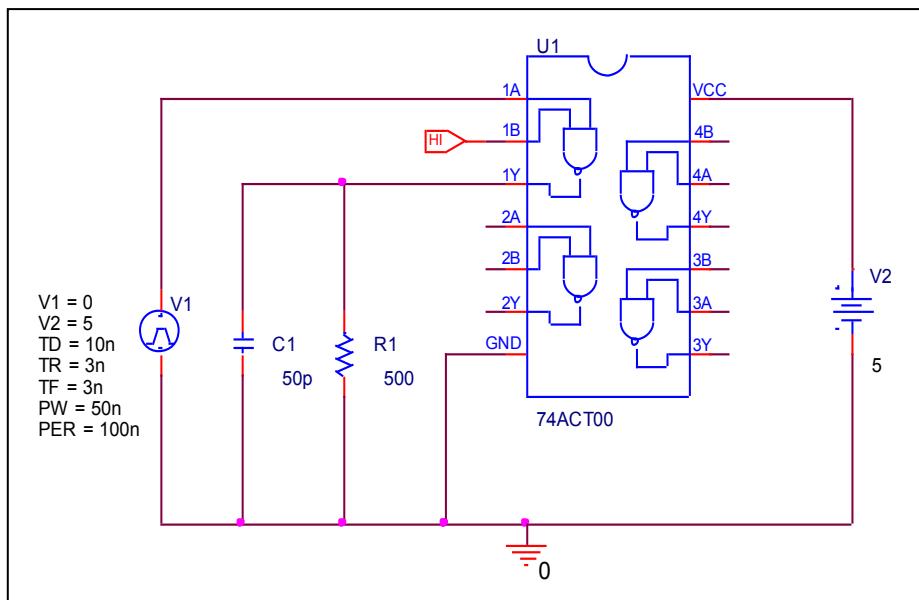
$V_{CC} = 4.5V$	Measurement	Simulation	%Error
$V_{OH}(V)$	4.5	4.4994	-0.013
$V_{OL}(V)$	0	0	0

Propagation Delay Time

Circuit simulation result



Evaluation circuit



Comparison table

$C_L = 50\text{pF}, R_L = 500\Omega, T_r = T_f = 3\text{ns}$	Measurement	Simulation	%Error
$t_{pLH} (\text{ns})$	4.7	4.7709	1.509
$t_{pHL} (\text{ns})$	4.7	4.7899	1.913